## Notice of References Cited Application/Control No. 09/806,090 Examiner N. Bhat Applicant(s)/Patent Under Reexamination SEKIYA, KUNIO Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,277,242	08-2001	Archer et al.	162/111
*	В	US-6,454,901	09-2002	Sekiya et al.	162/111
*	C	US-5,389,204	02-1995	Ampulski, Robert S.	162/135
	D	US-			
	Ш	US-			
	Ľ.	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	K	US-			
	L	US-			-
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 1 124 005	08-2001	EPO	Sekiya	
*	0	JP 07-292591	11-1995	Japan	Sekiya	
*	Р	JP 2000-345489	12-2000	Japan	Sekiya et al.	
	Q					
	R					
	s					
·	T					

## **NON-PATENT DOCUMENTS**

	HOTH ALERI DOCUMENTS						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.